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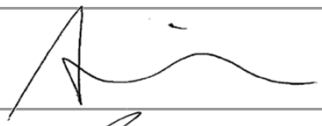
Product/Process Change Notification

PCN#	Effective Date	Issue Date
2019-04-01C-01	2019/7/1	2019/4/1
PCN Classification	Product Category	
Major	MOSFET	
Subject		
Process Optimization		
Affected Product(s)		
SSD15P10-C		
Description of Change(s)		
In order to enhance the effectiveness of the product, we change the wafer size from 6-inch to 8-inch.		
Content of Change(s)		
Wafer size		
Impact(s)		
N/A		
Attachment(s)		
Reliability Test Report.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

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Electrical Comparison Chart

Symbol	SPEC.	original 6' wafer (typ.)	new 8' wafer (typ.)	Unit
VDS	≧ -100V	-111.8	-108.8	V
IGSS	≦ -100nA	-3	-4.1	nA
IDSS	≦ -1uA	-8.6	-9	nA
VGS(th)	-1~-2.5V	-1.54	-1.7	V
Rdson(@ -10V)	≦90mΩ	70.5	67.8	mΩ
Rdson(@ -4.5V)	≦110mΩ	76.2	75.1	mΩ
VSD(@ -2A)	≦ -1.2V	-0.73	-0.74	V
Qg	typ. 29.2nC	49.68	48.54	nC
Qgs	typ. 4nC	11.4	9.57	nC
Qgd	typ. 8.5nC	11.64	10.32	nC
Td(on)	typ. 8.8ns	9.2	6.4	ns
Tr	typ. 17.2ns	19.6	19.2	ns
Td(off)	typ. 86.2ns	68.8	108.4	ns
Tf	typ. 63ns	39.6	49	ns
Ciss	typ. 1726pF	2998	2928	pF
Coss	typ. 104pF	123	120	pF
Crss	typ. 71pF	73	73	pF

SeCoS Corporation

Reliability Testing Summary Report

Date: 2019/03/28 Document No.: SM19 -03-15P10

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SSD15P10-C	150 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SSD15P10-C	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SSD15P10-C	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SSD15P10-C	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SSD15P10-C	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SSD15P10-C	85 ± 2℃, RH=85±5%, 80%VR, 1000 hrs		77	0	0	ACC
Solderability	SSD15P10-C	245 ± 5℃, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2019.02.01 Testing End Date: 2019.03.28

Tester: Leo Hsia Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 25℃
Test Date: 2019.02.01
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-108.5V	-8.951nA	67.1mΩ
2	-109.0V	-9.099nA	68.9mΩ
3	-109.0V	-9.083nA	68.2mΩ
4	-109.4V	-9.196nA	68.2mΩ
5	-109.2V	-9.128nA	68.2mΩ
6	-109.1V	-8.853nA	68.4mΩ
7	-108.7V	-9.180nA	68.1mΩ
8	-109.8V	-9.086nA	68.8mΩ
9	-108.9V	-9.149nA	67.2mΩ
10	-108.6V	-8.945nA	68.3mΩ
11	-108.8V	-9.212nA	67.7mΩ
12	-109.6V	-8.959nA	66.6mΩ
13	-108.3V	-8.949nA	68.5mΩ
14	-109.0V	-8.961nA	67.9mΩ
15	-109.1V	-9.113nA	66.9mΩ
16	-109.5V	-9.131nA	67.7mΩ
17	-108.2V	-8.896nA	67.4mΩ
18	-108.3V	-9.001nA	67.9mΩ
19	-108.3V	-8.896nA	67.9mΩ
20	-108.4V	-9.052nA	67.6mΩ
21	-109.1V	-8.914nA	67.6mΩ
22	-109.5V	-9.175nA	68.4mΩ
23	-109.7V	-9.191nA	68.1mΩ
24	-109.5V	-8.962nA	67.1mΩ
25	-109.6V	-9.127nA	67.3mΩ
26	-109.4V	-8.997nA	67.0mΩ
27	-109.7V	-8.972nA	67.1mΩ
28	-109.9V	-9.100nA	68.6mΩ
29	-108.2V	-8.983nA	66.8mΩ
30	-109.7V	-8.899nA	67.4mΩ

SeCoS Corporation

Electrical Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 25℃
Test Date: 2019.02.01
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
31	-109.2V	-9.177nA	67.5mΩ
32	-108.4V	-8.960nA	67.0mΩ
33	-108.6V	-8.877nA	67.7mΩ
34	-109.9V	-9.045nA	68.6mΩ
35	-108.9V	-9.026nA	68.1mΩ
36	-108.1V	-8.900nA	68.6mΩ
37	-108.8V	-8.899nA	66.9mΩ
38	-108.8V	-8.906nA	67.8mΩ
39	-108.0V	-9.137nA	66.8mΩ
40	-109.7V	-9.205nA	67.5mΩ
41	-108.4V	-9.041nA	66.8mΩ
42	-108.2V	-8.955nA	68.3mΩ
43	-109.7V	-8.976nA	68.4mΩ
44	-109.1V	-9.020nA	68.8mΩ
45	-109.1V	-9.080nA	68.8mΩ
46	-108.1V	-8.877nA	66.7mΩ
47	-109.3V	-9.006nA	68.0mΩ
48	-108.7V	-8.928nA	67.2mΩ
49	-108.4V	-8.897nA	67.5mΩ
50	-108.3V	-8.885nA	68.5mΩ
51	-108.2V	-9.112nA	67.7mΩ
52	-108.3V	-9.194nA	68.7mΩ
53	-109.4V	-9.034nA	68.2mΩ
54	-109.8V	-8.904nA	67.7mΩ
55	-108.8V	-9.210nA	66.7mΩ
56	-109.1V	-9.184nA	67.1mΩ
57	-108.1V	-9.104nA	67.6mΩ
58	-108.4V	-9.135nA	68.2mΩ
59	-108.6V	-9.023nA	67.4mΩ
60	-109.1V	-8.861nA	68.7mΩ

SeCoS Corporation

Electrical Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 25℃
Test Date: 2019.02.01
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
61	-109.0V	-9.237nA	68.1mΩ
62	-109.9V	-9.002nA	67.9mΩ
63	-109.2V	-9.090nA	67.0mΩ
64	-108.0V	-8.995nA	68.8mΩ
65	-109.1V	-8.887nA	67.4mΩ
66	-108.2V	-8.960nA	66.7mΩ
67	-108.7V	-9.194nA	68.0mΩ
68	-109.6V	-8.938nA	68.9mΩ
69	-109.5V	-9.084nA	68.5mΩ
70	-108.3V	-9.064nA	67.2mΩ
71	-109.4V	-9.201nA	68.8mΩ
72	-109.6V	-8.853nA	66.6mΩ
73	-108.1V	-9.111nA	68.1mΩ
74	-109.7V	-9.200nA	67.9mΩ
75	-109.0V	-8.921nA	68.6mΩ
76	-108.3V	-9.108nA	67.6mΩ
77	-109.7V	-9.132nA	67.2mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-108.7V	-8.980nA	68.6mΩ	-109.3V	-9.170nA	68.1mΩ
2	-109.7V	-8.997nA	68.0mΩ	-109.4V	-9.011nA	66.7mΩ
3	-109.6V	-8.899nA	67.7mΩ	-108.4V	-9.219nA	68.8mΩ
4	-108.7V	-8.861nA	67.1mΩ	-109.8V	-9.039nA	66.7mΩ
5	-109.5V	-9.137nA	68.8mΩ	-110.0V	-9.015nA	68.0mΩ
6	-108.7V	-9.007nA	66.7mΩ	-108.7V	-8.930nA	67.0mΩ
7	-108.7V	-9.193nA	66.8mΩ	-109.5V	-9.067nA	68.8mΩ
8	-109.2V	-9.032nA	68.4mΩ	-108.1V	-8.903nA	68.2mΩ
9	-108.0V	-8.925nA	68.3mΩ	-109.6V	-9.221nA	67.2mΩ
10	-108.2V	-9.054nA	67.7mΩ	-109.4V	-8.874nA	66.6mΩ
11	-110.0V	-9.065nA	67.5mΩ	-108.5V	-8.899nA	67.6mΩ
12	-109.6V	-9.026nA	69.0mΩ	-109.6V	-9.095nA	68.3mΩ
13	-108.4V	-9.223nA	67.1mΩ	-109.6V	-8.960nA	66.6mΩ
14	-108.5V	-9.129nA	68.7mΩ	-108.7V	-9.002nA	67.2mΩ
15	-108.0V	-9.204nA	67.5mΩ	-108.2V	-8.944nA	68.4mΩ
16	-108.8V	-9.207nA	68.0mΩ	-108.2V	-9.092nA	68.4mΩ
17	-110.0V	-8.854nA	68.7mΩ	-108.3V	-9.008nA	68.6mΩ
18	-108.3V	-8.866nA	67.2mΩ	-109.1V	-9.136nA	68.0mΩ
19	-108.3V	-9.110nA	67.2mΩ	-108.3V	-8.980nA	68.8mΩ
20	-109.4V	-9.225nA	67.8mΩ	-109.7V	-9.073nA	68.9mΩ
21	-109.9V	-9.204nA	67.1mΩ	-108.1V	-9.043nA	67.2mΩ
22	-109.6V	-8.859nA	68.8mΩ	-108.4V	-9.176nA	68.2mΩ
23	-110.0V	-9.128nA	68.6mΩ	-108.6V	-8.987nA	67.9mΩ
24	-108.6V	-9.046nA	67.8mΩ	-108.9V	-9.238nA	68.3mΩ
25	-109.6V	-9.084nA	67.9mΩ	-109.8V	-8.881nA	67.2mΩ
26	-109.7V	-9.186nA	68.3mΩ	-109.5V	-8.908nA	68.4mΩ
27	-109.1V	-8.870nA	68.6mΩ	-109.3V	-9.012nA	68.2mΩ
28	-109.8V	-9.048nA	68.5mΩ	-109.8V	-8.923nA	67.8mΩ
29	-108.3V	-8.897nA	68.0mΩ	-108.9V	-9.124nA	68.8mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-109.4V	-9.025nA	68.3mΩ	-109.3V	-9.009nA	67.5mΩ
31	-109.4V	-9.017nA	67.4mΩ	-108.6V	-8.946nA	67.0mΩ
32	-108.3V	-8.892nA	66.8mΩ	-109.9V	-8.979nA	68.9mΩ
33	-109.3V	-9.183nA	67.3mΩ	-108.1V	-9.021nA	66.9mΩ
34	-108.5V	-8.991nA	67.7mΩ	-108.3V	-8.905nA	68.9mΩ
35	-108.6V	-9.214nA	68.6mΩ	-108.7V	-9.079nA	68.3mΩ
36	-108.9V	-8.879nA	68.6mΩ	-108.8V	-9.172nA	68.1mΩ
37	-108.0V	-9.111nA	67.0mΩ	-109.3V	-8.998nA	67.6mΩ
38	-108.6V	-9.077nA	67.7mΩ	-108.5V	-9.131nA	67.5mΩ
39	-108.0V	-8.857nA	68.3mΩ	-108.3V	-9.009nA	67.7mΩ
40	-109.3V	-8.874nA	68.4mΩ	-108.1V	-9.007nA	67.1mΩ
41	-109.6V	-8.906nA	68.2mΩ	-109.0V	-9.162nA	66.6mΩ
42	-110.0V	-9.142nA	66.6mΩ	-109.8V	-8.854nA	68.5mΩ
43	-108.1V	-8.989nA	68.3mΩ	-108.6V	-8.948nA	68.5mΩ
44	-108.1V	-9.139nA	68.9mΩ	-108.8V	-9.115nA	68.2mΩ
45	-109.2V	-8.973nA	66.8mΩ	-108.1V	-8.964nA	67.3mΩ
46	-108.6V	-9.028nA	68.2mΩ	-108.5V	-9.081nA	68.5mΩ
47	-108.3V	-9.179nA	68.8mΩ	-108.0V	-9.104nA	67.6mΩ
48	-108.2V	-9.048nA	67.1mΩ	-109.6V	-9.091nA	66.8mΩ
49	-108.3V	-9.146nA	68.5mΩ	-108.5V	-9.034nA	67.6mΩ
50	-109.3V	-9.162nA	68.0mΩ	-108.1V	-9.107nA	67.5mΩ
51	-109.6V	-9.000nA	68.7mΩ	-108.9V	-9.059nA	66.8mΩ
52	-109.6V	-9.146nA	67.2mΩ	-108.2V	-9.195nA	68.7mΩ
53	-108.4V	-8.872nA	68.3mΩ	-108.4V	-9.040nA	67.3mΩ
54	-109.4V	-8.861nA	67.8mΩ	-108.0V	-9.108nA	67.4mΩ
55	-108.2V	-8.916nA	66.6mΩ	-109.9V	-9.076nA	67.8mΩ
56	-108.6V	-9.074nA	68.6mΩ	-108.3V	-9.170nA	67.2mΩ
57	-108.0V	-8.975nA	67.3mΩ	-109.2V	-8.852nA	68.6mΩ
58	-110.0V	-8.986nA	67.3mΩ	-109.7V	-8.972nA	67.9mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-108.9V	-9.101nA	68.2mΩ	-109.5V	-8.911nA	67.4mΩ
60	-108.9V	-8.938nA	68.6mΩ	-109.1V	-9.121nA	67.9mΩ
61	-108.9V	-8.850nA	67.3mΩ	-109.5V	-8.911nA	67.7mΩ
62	-108.0V	-9.143nA	69.0mΩ	-108.5V	-9.080nA	68.1mΩ
63	-109.8V	-9.161nA	68.9mΩ	-108.0V	-8.930nA	68.6mΩ
64	-109.3V	-8.997nA	66.8mΩ	-109.5V	-9.022nA	68.4mΩ
65	-109.8V	-8.905nA	68.6mΩ	-109.0V	-8.999nA	66.8mΩ
66	-109.8V	-8.949nA	67.4mΩ	-108.1V	-9.149nA	66.9mΩ
67	-109.9V	-8.940nA	67.3mΩ	-108.9V	-8.917nA	68.2mΩ
68	-109.5V	-9.064nA	67.1mΩ	-109.8V	-8.941nA	68.4mΩ
69	-109.3V	-8.967nA	68.2mΩ	-108.6V	-9.037nA	67.4mΩ
70	-108.7V	-9.032nA	67.4mΩ	-109.6V	-8.941nA	67.6mΩ
71	-109.4V	-9.203nA	68.7mΩ	-108.5V	-9.128nA	66.9mΩ
72	-108.5V	-9.015nA	68.7mΩ	-109.7V	-9.052nA	68.8mΩ
73	-109.2V	-8.848nA	68.0mΩ	-108.3V	-9.195nA	68.4mΩ
74	-109.5V	-9.214nA	68.6mΩ	-109.8V	-8.857nA	68.4mΩ
75	-110.0V	-8.907nA	66.9mΩ	-108.9V	-9.043nA	68.4mΩ
76	-108.8V	-9.013nA	67.1mΩ	-108.1V	-8.914nA	68.8mΩ
77	-108.7V	-8.868nA	68.8mΩ	-109.6V	-8.958nA	68.7mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 150℃, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-109.1V	-9.185nA	69.0mΩ	-109.0V	-9.208nA	67.6mΩ
2	-110.0V	-9.030nA	67.2mΩ	-109.3V	-9.155nA	68.8mΩ
3	-109.0V	-9.013nA	68.9mΩ	-108.8V	-9.015nA	66.9mΩ
4	-109.9V	-8.955nA	68.6mΩ	-108.5V	-8.912nA	68.2mΩ
5	-109.6V	-9.225nA	67.4mΩ	-109.8V	-9.224nA	66.8mΩ
6	-109.7V	-8.937nA	69.0mΩ	-109.2V	-9.153nA	68.9mΩ
7	-108.2V	-9.095nA	68.4mΩ	-108.5V	-9.073nA	68.9mΩ
8	-109.3V	-9.101nA	67.1mΩ	-108.9V	-9.056nA	66.8mΩ
9	-109.5V	-8.864nA	68.0mΩ	-108.4V	-9.144nA	67.0mΩ
10	-109.2V	-8.932nA	67.2mΩ	-109.4V	-9.152nA	67.2mΩ
11	-109.9V	-9.010nA	66.9mΩ	-109.7V	-9.016nA	66.6mΩ
12	-108.1V	-9.212nA	67.3mΩ	-110.0V	-9.203nA	67.3mΩ
13	-109.1V	-8.998nA	68.5mΩ	-108.1V	-9.057nA	66.9mΩ
14	-108.6V	-8.881nA	67.1mΩ	-108.2V	-8.955nA	66.6mΩ
15	-110.0V	-9.155nA	66.8mΩ	-108.4V	-9.155nA	68.3mΩ
16	-109.5V	-8.917nA	68.8mΩ	-109.2V	-9.046nA	67.4mΩ
17	-109.8V	-9.132nA	68.1mΩ	-109.1V	-9.135nA	68.5mΩ
18	-108.5V	-9.186nA	68.3mΩ	-108.6V	-9.197nA	66.9mΩ
19	-108.4V	-9.113nA	68.6mΩ	-108.0V	-9.101nA	69.0mΩ
20	-109.9V	-9.154nA	68.8mΩ	-108.1V	-8.976nA	67.6mΩ
21	-108.5V	-9.174nA	67.3mΩ	-108.1V	-9.246nA	68.2mΩ
22	-109.0V	-8.999nA	67.8mΩ	-110.0V	-9.009nA	68.0mΩ
23	-109.5V	-9.074nA	66.8mΩ	-109.0V	-8.867nA	68.3mΩ
24	-109.1V	-9.218nA	68.7mΩ	-110.0V	-8.925nA	66.8mΩ
25	-109.1V	-9.000nA	68.5mΩ	-109.6V	-9.029nA	67.2mΩ
26	-108.8V	-8.978nA	66.9mΩ	-108.7V	-9.198nA	67.0mΩ
27	-108.5V	-8.871nA	68.4mΩ	-109.9V	-9.113nA	68.0mΩ
28	-109.7V	-8.866nA	68.0mΩ	-109.6V	-9.006nA	67.5mΩ
29	-109.8V	-8.870nA	68.3mΩ	-109.0V	-9.210nA	66.7mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 150℃, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-108.4V	-9.205nA	68.1mΩ	-109.7V	-9.112nA	67.0mΩ
31	-109.6V	-9.122nA	67.2mΩ	-108.7V	-9.206nA	68.0mΩ
32	-109.5V	-9.023nA	68.4mΩ	-108.7V	-8.863nA	67.1mΩ
33	-108.7V	-9.120nA	68.7mΩ	-109.3V	-9.004nA	68.5mΩ
34	-108.9V	-8.936nA	68.3mΩ	-109.7V	-8.936nA	68.9mΩ
35	-109.3V	-9.114nA	68.5mΩ	-109.7V	-8.897nA	68.0mΩ
36	-108.3V	-8.966nA	66.9mΩ	-109.2V	-9.167nA	67.8mΩ
37	-108.4V	-9.011nA	67.4mΩ	-108.6V	-9.031nA	68.2mΩ
38	-108.0V	-9.202nA	67.1mΩ	-109.2V	-9.155nA	68.1mΩ
39	-109.8V	-9.188nA	66.6mΩ	-109.1V	-9.149nA	67.6mΩ
40	-109.3V	-9.063nA	67.0mΩ	-108.5V	-9.064nA	68.9mΩ
41	-109.7V	-8.878nA	67.1mΩ	-109.4V	-9.036nA	67.0mΩ
42	-109.2V	-9.060nA	68.7mΩ	-109.9V	-8.965nA	68.1mΩ
43	-109.3V	-8.899nA	67.8mΩ	-109.9V	-9.002nA	67.4mΩ
44	-109.3V	-8.870nA	66.9mΩ	-109.6V	-9.147nA	68.8mΩ
45	-109.8V	-8.875nA	68.2mΩ	-108.7V	-9.127nA	67.7mΩ
46	-108.0V	-8.918nA	66.8mΩ	-108.7V	-8.958nA	67.1mΩ
47	-109.2V	-9.136nA	67.3mΩ	-109.3V	-9.029nA	67.1mΩ
48	-109.6V	-9.213nA	68.5mΩ	-109.1V	-9.028nA	67.9mΩ
49	-108.8V	-8.941nA	67.4mΩ	-108.1V	-8.879nA	68.4mΩ
50	-108.1V	-9.065nA	68.3mΩ	-108.3V	-9.012nA	67.1mΩ
51	-109.8V	-8.869nA	67.3mΩ	-108.9V	-9.165nA	67.7mΩ
52	-108.8V	-9.039nA	66.8mΩ	-108.5V	-9.193nA	67.7mΩ
53	-108.7V	-9.216nA	68.4mΩ	-108.4V	-8.920nA	67.0mΩ
54	-108.4V	-9.163nA	68.4mΩ	-108.7V	-9.075nA	66.9mΩ
55	-109.3V	-9.144nA	68.4mΩ	-109.9V	-8.883nA	68.6mΩ
56	-108.3V	-9.128nA	68.8mΩ	-109.2V	-9.005nA	66.6mΩ
57	-108.2V	-9.203nA	68.6mΩ	-108.7V	-9.158nA	67.6mΩ
58	-109.8V	-8.847nA	67.9mΩ	-108.2V	-9.159nA	66.8mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 150℃, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-109.1V	-8.934nA	67.3mΩ	-108.3V	-8.912nA	68.5mΩ
60	-108.4V	-9.117nA	67.9mΩ	-109.9V	-9.175nA	68.6mΩ
61	-109.0V	-8.973nA	67.9mΩ	-108.1V	-9.122nA	67.1mΩ
62	-108.1V	-8.984nA	67.3mΩ	-109.9V	-8.884nA	68.3mΩ
63	-109.4V	-9.137nA	67.3mΩ	-108.1V	-9.202nA	68.8mΩ
64	-109.6V	-9.016nA	66.7mΩ	-108.5V	-9.138nA	68.7mΩ
65	-109.6V	-9.214nA	68.2mΩ	-110.0V	-8.905nA	67.3mΩ
66	-109.7V	-9.186nA	68.4mΩ	-108.3V	-8.996nA	68.2mΩ
67	-108.6V	-8.949nA	67.6mΩ	-109.2V	-8.969nA	67.6mΩ
68	-108.2V	-8.897nA	68.5mΩ	-109.7V	-9.092nA	69.0mΩ
69	-109.5V	-9.152nA	68.2mΩ	-108.5V	-9.121nA	68.7mΩ
70	-108.8V	-8.915nA	68.0mΩ	-109.1V	-8.898nA	67.7mΩ
71	-108.8V	-9.185nA	67.0mΩ	-108.1V	-9.042nA	67.0mΩ
72	-108.8V	-9.006nA	68.5mΩ	-108.4V	-9.129nA	68.2mΩ
73	-109.3V	-9.118nA	67.5mΩ	-108.0V	-8.875nA	68.1mΩ
74	-108.0V	-9.216nA	68.7mΩ	-108.7V	-8.947nA	67.3mΩ
75	-109.1V	-8.853nA	67.4mΩ	-109.1V	-9.028nA	66.6mΩ
76	-108.6V	-9.200nA	67.8mΩ	-109.9V	-8.991nA	66.9mΩ
77	-108.4V	-8.987nA	67.6mΩ	-109.1V	-9.135nA	67.5mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2019.02.11 ~ 2019.02.19
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-109.6V	-9.151nA	68.6mΩ	-108.7V	-8.863nA	67.4mΩ
2	-109.7V	-9.027nA	67.8mΩ	-109.3V	-8.849nA	69.0mΩ
3	-109.5V	-9.079nA	68.3mΩ	-109.4V	-8.924nA	67.2mΩ
4	-109.8V	-8.921nA	68.9mΩ	-109.3V	-9.013nA	67.8mΩ
5	-109.7V	-9.091nA	67.6mΩ	-108.9V	-8.978nA	68.7mΩ
6	-108.5V	-8.995nA	66.8mΩ	-108.2V	-9.146nA	67.2mΩ
7	-108.6V	-8.911nA	67.1mΩ	-108.9V	-9.131nA	67.1mΩ
8	-109.3V	-9.024nA	67.6mΩ	-108.9V	-9.116nA	68.7mΩ
9	-108.3V	-8.950nA	68.4mΩ	-109.6V	-9.096nA	68.9mΩ
10	-109.3V	-8.949nA	67.8mΩ	-109.1V	-9.220nA	68.1mΩ
11	-108.7V	-8.920nA	67.0mΩ	-108.4V	-9.135nA	69.0mΩ
12	-109.3V	-9.159nA	68.4mΩ	-108.1V	-9.075nA	67.8mΩ
13	-109.1V	-8.895nA	67.5mΩ	-109.0V	-8.861nA	67.6mΩ
14	-109.8V	-9.161nA	68.3mΩ	-108.1V	-9.107nA	66.8mΩ
15	-109.8V	-8.902nA	66.7mΩ	-108.0V	-9.065nA	67.9mΩ
16	-109.7V	-9.070nA	66.8mΩ	-109.8V	-8.848nA	68.1mΩ
17	-109.0V	-8.937nA	68.3mΩ	-109.4V	-9.180nA	68.8mΩ
18	-108.9V	-9.174nA	68.3mΩ	-109.3V	-9.186nA	68.6mΩ
19	-108.1V	-8.861nA	68.1mΩ	-108.6V	-8.865nA	67.5mΩ
20	-109.8V	-9.096nA	68.8mΩ	-108.2V	-8.894nA	67.6mΩ
21	-109.5V	-9.065nA	68.7mΩ	-109.0V	-9.087nA	68.3mΩ
22	-108.6V	-9.023nA	68.4mΩ	-109.9V	-9.155nA	68.4mΩ
23	-108.9V	-8.904nA	67.3mΩ	-109.3V	-9.231nA	67.4mΩ
24	-109.0V	-9.231nA	67.4mΩ	-109.6V	-8.941nA	68.7mΩ
25	-109.1V	-9.083nA	68.5mΩ	-109.4V	-9.212nA	68.5mΩ
26	-109.5V	-9.245nA	67.0mΩ	-108.6V	-9.089nA	68.7mΩ
27	-109.7V	-9.228nA	67.4mΩ	-108.7V	-9.210nA	68.6mΩ
28	-109.1V	-9.197nA	67.2mΩ	-108.0V	-9.098nA	68.7mΩ
29	-108.9V	-8.899nA	67.3mΩ	-109.5V	-9.051nA	69.0mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2019.02.11 ~ 2019.02.19
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-109.7V	-8.996nA	68.9mΩ	-109.4V	-8.855nA	66.9mΩ
31	-108.7V	-9.205nA	68.2mΩ	-108.5V	-9.005nA	66.8mΩ
32	-108.3V	-9.175nA	66.9mΩ	-109.3V	-8.961nA	68.4mΩ
33	-110.0V	-9.017nA	66.7mΩ	-109.3V	-9.016nA	66.8mΩ
34	-109.2V	-9.015nA	68.8mΩ	-108.6V	-8.991nA	67.7mΩ
35	-109.4V	-8.916nA	66.7mΩ	-109.3V	-8.956nA	67.6mΩ
36	-110.0V	-8.984nA	68.9mΩ	-108.1V	-9.165nA	68.2mΩ
37	-108.0V	-9.240nA	68.2mΩ	-109.7V	-9.154nA	67.3mΩ
38	-108.6V	-8.853nA	67.2mΩ	-109.7V	-9.216nA	67.1mΩ
39	-108.1V	-9.147nA	67.2mΩ	-109.5V	-9.115nA	68.8mΩ
40	-109.6V	-8.897nA	66.9mΩ	-108.1V	-9.097nA	67.8mΩ
41	-109.0V	-9.030nA	67.6mΩ	-108.8V	-8.896nA	67.5mΩ
42	-108.2V	-9.006nA	67.6mΩ	-108.2V	-8.978nA	67.2mΩ
43	-108.1V	-8.934nA	66.7mΩ	-109.4V	-9.092nA	67.6mΩ
44	-108.4V	-9.160nA	67.3mΩ	-109.4V	-8.938nA	68.5mΩ
45	-108.1V	-9.093nA	68.0mΩ	-109.1V	-9.076nA	68.0mΩ
46	-108.8V	-9.208nA	66.7mΩ	-108.1V	-9.020nA	68.7mΩ
47	-109.5V	-9.166nA	67.0mΩ	-109.2V	-9.182nA	68.2mΩ
48	-109.1V	-8.908nA	67.8mΩ	-108.0V	-9.175nA	67.9mΩ
49	-108.1V	-9.243nA	67.0mΩ	-109.7V	-8.859nA	67.8mΩ
50	-110.0V	-9.183nA	68.8mΩ	-109.6V	-8.960nA	66.8mΩ
51	-109.4V	-9.096nA	68.5mΩ	-109.7V	-8.938nA	68.6mΩ
52	-109.5V	-9.098nA	66.9mΩ	-109.7V	-9.062nA	68.7mΩ
53	-109.6V	-8.967nA	67.1mΩ	-109.7V	-8.956nA	67.7mΩ
54	-108.7V	-9.209nA	67.5mΩ	-108.4V	-8.905nA	67.4mΩ
55	-108.0V	-8.973nA	68.5mΩ	-108.2V	-8.852nA	67.9mΩ
56	-109.8V	-8.880nA	67.3mΩ	-108.1V	-9.218nA	68.6mΩ
57	-108.9V	-9.106nA	68.4mΩ	-108.8V	-9.018nA	67.9mΩ
58	-109.6V	-9.017nA	68.3mΩ	-109.1V	-9.014nA	67.4mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2019.02.11 ~ 2019.02.19
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-109.4V	-8.977nA	68.5mΩ	-108.1V	-9.134nA	68.9mΩ
60	-109.4V	-9.207nA	68.3mΩ	-108.6V	-8.919nA	68.2mΩ
61	-109.3V	-9.095nA	66.7mΩ	-108.2V	-8.999nA	66.9mΩ
62	-109.5V	-8.890nA	67.5mΩ	-108.9V	-9.033nA	68.7mΩ
63	-109.9V	-8.888nA	69.0mΩ	-109.5V	-9.120nA	66.8mΩ
64	-108.3V	-9.122nA	67.1mΩ	-108.2V	-8.926nA	67.4mΩ
65	-108.6V	-8.944nA	67.0mΩ	-109.5V	-8.932nA	66.7mΩ
66	-108.5V	-8.957nA	68.0mΩ	-109.9V	-8.962nA	68.7mΩ
67	-109.1V	-9.237nA	66.7mΩ	-109.0V	-9.008nA	67.8mΩ
68	-109.2V	-8.861nA	67.7mΩ	-108.1V	-9.035nA	67.8mΩ
69	-108.5V	-8.910nA	68.1mΩ	-109.9V	-8.938nA	67.6mΩ
70	-109.1V	-9.114nA	67.0mΩ	-109.5V	-9.224nA	67.9mΩ
71	-109.8V	-9.157nA	67.4mΩ	-109.9V	-9.247nA	69.0mΩ
72	-108.5V	-9.085nA	66.8mΩ	-108.6V	-9.170nA	68.2mΩ
73	-109.3V	-8.860nA	68.4mΩ	-108.0V	-8.863nA	67.6mΩ
74	-109.5V	-9.210nA	68.1mΩ	-109.0V	-9.047nA	66.9mΩ
75	-108.6V	-8.917nA	68.1mΩ	-110.0V	-9.228nA	68.8mΩ
76	-109.7V	-8.918nA	67.5mΩ	-109.4V	-8.925nA	66.9mΩ
77	-108.3V	-9.240nA	68.8mΩ	-108.7V	-9.143nA	67.7mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2019.02.01 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-109.4V	-9.134nA	68.3mΩ	-109.6V	-9.088nA	68.8mΩ
2	-109.9V	-8.958nA	66.9mΩ	-109.2V	-9.001nA	68.8mΩ
3	-109.0V	-9.170nA	67.8mΩ	-108.9V	-9.158nA	67.4mΩ
4	-109.1V	-9.102nA	68.9mΩ	-108.3V	-8.890nA	67.8mΩ
5	-109.5V	-9.225nA	68.0mΩ	-108.3V	-9.002nA	67.7mΩ
6	-110.0V	-8.945nA	66.6mΩ	-108.3V	-9.215nA	68.2mΩ
7	-108.8V	-8.961nA	66.9mΩ	-108.9V	-9.008nA	68.9mΩ
8	-109.9V	-8.932nA	67.7mΩ	-109.7V	-9.058nA	68.8mΩ
9	-108.7V	-9.159nA	68.5mΩ	-109.9V	-9.127nA	67.6mΩ
10	-109.0V	-9.050nA	68.8mΩ	-108.7V	-8.850nA	67.9mΩ
11	-109.6V	-8.861nA	67.3mΩ	-109.2V	-9.077nA	66.9mΩ
12	-108.0V	-8.928nA	68.7mΩ	-108.7V	-8.862nA	68.1mΩ
13	-108.8V	-9.005nA	68.8mΩ	-109.3V	-8.888nA	66.7mΩ
14	-109.1V	-9.248nA	68.2mΩ	-108.6V	-9.189nA	66.8mΩ
15	-108.2V	-9.244nA	68.7mΩ	-109.0V	-8.971nA	66.6mΩ
16	-109.1V	-8.971nA	68.9mΩ	-109.4V	-9.013nA	68.3mΩ
17	-108.7V	-9.104nA	68.9mΩ	-107.9V	-9.187nA	67.0mΩ
18	-108.0V	-9.193nA	66.7mΩ	-108.2V	-8.933nA	67.0mΩ
19	-108.4V	-8.853nA	66.9mΩ	-108.9V	-9.189nA	67.6mΩ
20	-108.3V	-9.089nA	68.3mΩ	-108.0V	-9.150nA	67.0mΩ
21	-109.1V	-9.170nA	66.9mΩ	-109.5V	-8.992nA	68.2mΩ
22	-109.6V	-8.990nA	68.0mΩ	-109.1V	-8.997nA	67.9mΩ
23	-109.1V	-8.965nA	67.4mΩ	-109.4V	-9.032nA	68.2mΩ
24	-108.3V	-9.038nA	67.4mΩ	-109.4V	-8.947nA	67.1mΩ
25	-108.2V	-9.219nA	68.3mΩ	-109.7V	-8.939nA	67.2mΩ
26	-109.2V	-8.973nA	68.8mΩ	-108.7V	-9.243nA	68.5mΩ
27	-108.2V	-9.165nA	68.1mΩ	-108.8V	-9.210nA	68.2mΩ
28	-109.7V	-8.931nA	67.4mΩ	-108.5V	-9.141nA	68.7mΩ
29	-108.1V	-8.945nA	67.2mΩ	-109.2V	-9.016nA	67.4mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2019.02.01 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-110.0V	-9.135nA	67.7mΩ	-109.2V	-9.131nA	68.3mΩ
31	-108.9V	-9.208nA	68.0mΩ	-109.4V	-8.923nA	67.5mΩ
32	-108.7V	-9.181nA	67.1mΩ	-109.6V	-9.177nA	68.9mΩ
33	-108.6V	-9.248nA	68.0mΩ	-108.1V	-8.891nA	67.7mΩ
34	-110.0V	-9.154nA	66.7mΩ	-108.5V	-9.049nA	67.6mΩ
35	-109.1V	-9.243nA	66.7mΩ	-109.5V	-9.221nA	67.8mΩ
36	-108.6V	-9.061nA	68.8mΩ	-109.2V	-8.992nA	66.9mΩ
37	-110.0V	-9.123nA	68.5mΩ	-109.0V	-8.959nA	66.8mΩ
38	-109.6V	-8.936nA	66.9mΩ	-108.3V	-8.898nA	68.2mΩ
39	-108.4V	-8.890nA	67.3mΩ	-109.5V	-8.935nA	68.7mΩ
40	-109.6V	-8.854nA	66.9mΩ	-108.9V	-9.009nA	68.1mΩ
41	-108.6V	-8.894nA	67.5mΩ	-109.7V	-8.860nA	67.0mΩ
42	-108.3V	-8.930nA	67.0mΩ	-108.9V	-9.199nA	67.9mΩ
43	-109.3V	-9.027nA	67.9mΩ	-109.6V	-9.189nA	68.9mΩ
44	-108.1V	-9.129nA	67.0mΩ	-108.5V	-9.211nA	66.8mΩ
45	-108.2V	-8.923nA	67.7mΩ	-109.2V	-9.248nA	67.8mΩ
46	-108.5V	-9.006nA	67.3mΩ	-108.5V	-9.227nA	68.9mΩ
47	-109.9V	-8.912nA	68.2mΩ	-109.5V	-9.153nA	66.9mΩ
48	-110.0V	-8.946nA	68.5mΩ	-109.6V	-8.985nA	67.3mΩ
49	-108.8V	-9.112nA	66.8mΩ	-109.8V	-8.943nA	68.0mΩ
50	-109.7V	-9.130nA	68.2mΩ	-109.2V	-9.048nA	68.1mΩ
51	-108.3V	-9.147nA	68.4mΩ	-108.0V	-9.009nA	67.6mΩ
52	-109.0V	-8.957nA	68.9mΩ	-108.0V	-9.230nA	66.7mΩ
53	-108.6V	-8.910nA	67.1mΩ	-109.8V	-8.946nA	67.5mΩ
54	-108.9V	-9.053nA	68.5mΩ	-109.1V	-9.030nA	68.2mΩ
55	-109.0V	-8.909nA	68.9mΩ	-108.3V	-8.870nA	67.8mΩ
56	-108.8V	-9.054nA	67.4mΩ	-109.2V	-9.134nA	68.9mΩ
57	-109.2V	-9.127nA	68.6mΩ	-108.8V	-8.951nA	67.0mΩ
58	-109.1V	-8.950nA	66.8mΩ	-108.1V	-8.959nA	68.6mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2019.02.01 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-109.1V	-8.946nA	67.1mΩ	-108.3V	-9.246nA	68.3mΩ
60	-109.0V	-9.149nA	68.3mΩ	-108.4V	-8.982nA	67.8mΩ
61	-109.2V	-8.957nA	67.0mΩ	-110.0V	-8.955nA	67.8mΩ
62	-109.3V	-9.104nA	68.4mΩ	-109.4V	-9.053nA	68.3mΩ
63	-108.6V	-9.128nA	68.8mΩ	-108.4V	-9.047nA	67.5mΩ
64	-108.1V	-9.098nA	67.9mΩ	-109.5V	-8.860nA	68.0mΩ
65	-108.4V	-9.206nA	67.5mΩ	-109.9V	-9.150nA	67.6mΩ
66	-108.7V	-8.948nA	67.1mΩ	-109.4V	-9.145nA	68.3mΩ
67	-109.5V	-9.156nA	68.7mΩ	-109.8V	-9.085nA	67.2mΩ
68	-108.2V	-8.853nA	67.5mΩ	-108.6V	-8.961nA	67.1mΩ
69	-109.5V	-9.042nA	68.9mΩ	-109.0V	-9.060nA	67.3mΩ
70	-109.6V	-9.066nA	67.4mΩ	-108.8V	-9.004nA	66.8mΩ
71	-109.4V	-9.013nA	68.9mΩ	-108.4V	-8.946nA	68.0mΩ
72	-109.3V	-8.963nA	67.6mΩ	-108.1V	-9.197nA	68.6mΩ
73	-109.2V	-9.092nA	67.5mΩ	-108.5V	-8.871nA	68.3mΩ
74	-108.2V	-8.868nA	67.7mΩ	-108.6V	-9.068nA	68.8mΩ
75	-108.8V	-9.187nA	68.9mΩ	-109.7V	-8.957nA	68.7mΩ
76	-109.3V	-9.170nA	68.3mΩ	-109.8V	-9.032nA	67.0mΩ
77	-108.5V	-8.918nA	67.7mΩ	-108.4V	-8.951nA	68.5mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-108.0V	-8.883nA	67.5mΩ	-108.6V	-9.163nA	68.5mΩ
2	-109.1V	-9.102nA	67.1mΩ	-109.8V	-8.869nA	68.8mΩ
3	-107.9V	-9.079nA	68.9mΩ	-109.7V	-8.913nA	67.5mΩ
4	-108.6V	-8.896nA	67.4mΩ	-109.9V	-8.987nA	67.0mΩ
5	-108.9V	-9.127nA	68.0mΩ	-107.9V	-9.128nA	67.2mΩ
6	-108.0V	-9.003nA	68.8mΩ	-108.9V	-9.243nA	66.8mΩ
7	-109.2V	-9.171nA	68.6mΩ	-108.7V	-9.012nA	67.7mΩ
8	-109.7V	-8.851nA	68.7mΩ	-108.5V	-9.003nA	68.7mΩ
9	-109.9V	-8.852nA	68.6mΩ	-109.7V	-9.171nA	68.2mΩ
10	-109.9V	-9.021nA	67.2mΩ	-109.8V	-9.075nA	67.2mΩ
11	-109.8V	-8.867nA	68.8mΩ	-108.3V	-8.845nA	68.4mΩ
12	-108.7V	-8.899nA	66.7mΩ	-108.5V	-8.936nA	66.8mΩ
13	-108.1V	-9.022nA	67.4mΩ	-108.8V	-9.004nA	66.6mΩ
14	-108.6V	-8.920nA	67.6mΩ	-109.1V	-8.910nA	66.7mΩ
15	-109.9V	-9.159nA	67.1mΩ	-108.3V	-9.203nA	67.8mΩ
16	-109.2V	-8.870nA	68.6mΩ	-108.6V	-8.948nA	68.5mΩ
17	-108.4V	-8.980nA	68.8mΩ	-108.7V	-9.074nA	67.0mΩ
18	-109.2V	-8.879nA	67.9mΩ	-108.4V	-9.082nA	67.4mΩ
19	-108.4V	-9.210nA	68.4mΩ	-109.0V	-8.921nA	66.7mΩ
20	-108.2V	-8.992nA	67.9mΩ	-109.2V	-9.014nA	69.0mΩ
21	-108.0V	-9.097nA	68.3mΩ	-109.5V	-8.998nA	67.4mΩ
22	-109.1V	-9.194nA	68.7mΩ	-109.7V	-8.957nA	66.7mΩ
23	-108.7V	-8.961nA	69.0mΩ	-109.9V	-9.148nA	68.9mΩ
24	-109.0V	-9.172nA	67.4mΩ	-109.0V	-9.010nA	68.1mΩ
25	-108.0V	-9.172nA	69.0mΩ	-109.6V	-9.162nA	66.8mΩ
26	-110.0V	-9.232nA	67.5mΩ	-108.7V	-9.159nA	68.5mΩ
27	-108.7V	-9.152nA	69.0mΩ	-108.6V	-9.190nA	67.6mΩ
28	-108.9V	-9.181nA	66.8mΩ	-108.8V	-9.052nA	68.8mΩ
29	-108.9V	-9.066nA	69.0mΩ	-108.7V	-8.896nA	68.9mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-108.8V	-9.226nA	67.6mΩ	-109.5V	-8.876nA	68.6mΩ
31	-109.3V	-9.012nA	66.6mΩ	-109.1V	-9.173nA	66.8mΩ
32	-108.9V	-9.135nA	67.9mΩ	-108.8V	-9.079nA	67.9mΩ
33	-108.5V	-9.022nA	67.5mΩ	-108.0V	-9.088nA	68.7mΩ
34	-109.9V	-9.219nA	67.8mΩ	-108.9V	-8.892nA	66.9mΩ
35	-108.0V	-8.896nA	67.2mΩ	-109.5V	-9.152nA	68.5mΩ
36	-109.1V	-9.203nA	67.3mΩ	-109.8V	-8.982nA	69.0mΩ
37	-108.5V	-9.240nA	68.0mΩ	-109.0V	-9.158nA	66.9mΩ
38	-108.1V	-8.975nA	68.6mΩ	-108.1V	-9.245nA	67.5mΩ
39	-109.5V	-9.124nA	67.9mΩ	-109.8V	-9.003nA	68.0mΩ
40	-109.8V	-8.932nA	68.0mΩ	-108.6V	-9.040nA	68.2mΩ
41	-109.0V	-8.967nA	67.0mΩ	-108.7V	-9.125nA	68.7mΩ
42	-108.7V	-8.875nA	67.5mΩ	-109.9V	-9.143nA	66.8mΩ
43	-108.8V	-9.072nA	68.3mΩ	-109.2V	-9.123nA	66.8mΩ
44	-108.8V	-9.204nA	68.4mΩ	-109.6V	-8.901nA	66.6mΩ
45	-108.5V	-9.099nA	68.2mΩ	-109.5V	-9.048nA	68.5mΩ
46	-109.0V	-8.970nA	66.6mΩ	-108.9V	-9.026nA	68.0mΩ
47	-109.4V	-8.929nA	69.0mΩ	-109.8V	-8.984nA	68.1mΩ
48	-108.4V	-9.000nA	68.5mΩ	-109.7V	-9.097nA	66.7mΩ
49	-110.0V	-8.918nA	67.5mΩ	-108.0V	-8.891nA	67.8mΩ
50	-108.6V	-8.905nA	67.6mΩ	-108.7V	-8.940nA	68.3mΩ
51	-110.0V	-9.166nA	67.3mΩ	-108.8V	-9.114nA	67.3mΩ
52	-109.0V	-8.897nA	68.1mΩ	-108.5V	-8.948nA	66.9mΩ
53	-108.9V	-8.975nA	67.8mΩ	-109.0V	-9.106nA	67.6mΩ
54	-108.7V	-9.206nA	67.9mΩ	-109.4V	-8.872nA	66.8mΩ
55	-108.7V	-9.031nA	68.9mΩ	-108.2V	-8.891nA	67.3mΩ
56	-108.2V	-8.859nA	68.9mΩ	-108.8V	-8.971nA	69.0mΩ
57	-109.5V	-9.228nA	66.8mΩ	-109.1V	-8.936nA	66.8mΩ
58	-108.2V	-9.062nA	67.0mΩ	-108.4V	-8.991nA	68.9mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-108.9V	-8.892nA	66.9mΩ	-109.7V	-9.032nA	68.3mΩ
60	-109.0V	-8.915nA	69.0mΩ	-109.1V	-8.875nA	68.0mΩ
61	-108.5V	-9.046nA	67.8mΩ	-108.0V	-9.083nA	68.3mΩ
62	-109.1V	-9.074nA	67.0mΩ	-108.4V	-9.042nA	68.4mΩ
63	-108.9V	-9.075nA	66.7mΩ	-109.8V	-9.158nA	68.6mΩ
64	-109.9V	-9.076nA	68.1mΩ	-108.3V	-8.921nA	68.2mΩ
65	-109.8V	-9.193nA	68.0mΩ	-109.2V	-9.162nA	68.0mΩ
66	-108.0V	-9.205nA	68.8mΩ	-109.9V	-9.112nA	66.8mΩ
67	-109.8V	-8.893nA	67.5mΩ	-109.4V	-8.971nA	67.7mΩ
68	-109.8V	-9.068nA	68.4mΩ	-108.0V	-8.903nA	66.9mΩ
69	-109.3V	-9.231nA	67.0mΩ	-108.7V	-8.866nA	67.8mΩ
70	-108.7V	-9.195nA	67.8mΩ	-108.4V	-8.913nA	67.5mΩ
71	-109.2V	-8.849nA	68.2mΩ	-109.7V	-9.079nA	66.9mΩ
72	-108.8V	-8.948nA	68.4mΩ	-108.7V	-9.075nA	68.2mΩ
73	-108.4V	-8.914nA	67.8mΩ	-108.5V	-8.937nA	67.7mΩ
74	-107.9V	-9.105nA	67.2mΩ	-109.6V	-8.997nA	69.0mΩ
75	-109.7V	-8.962nA	67.6mΩ	-108.1V	-9.178nA	68.6mΩ
76	-108.8V	-8.965nA	67.1mΩ	-109.8V	-9.243nA	67.0mΩ
77	-109.6V	-9.191nA	68.3mΩ	-109.1V	-8.870nA	66.8mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-108.7V	-9.031nA	66.9mΩ	-109.0V	-8.953nA	68.1mΩ
2	-109.2V	-8.874nA	68.6mΩ	-110.0V	-8.907nA	68.6mΩ
3	-108.3V	-9.139nA	67.1mΩ	-108.5V	-8.888nA	67.2mΩ
4	-108.6V	-9.040nA	68.8mΩ	-108.6V	-9.120nA	66.9mΩ
5	-109.1V	-8.850nA	67.0mΩ	-110.0V	-9.228nA	67.5mΩ
6	-109.6V	-8.940nA	66.6mΩ	-109.3V	-8.969nA	67.2mΩ
7	-109.2V	-8.914nA	68.8mΩ	-108.2V	-8.958nA	66.8mΩ
8	-109.7V	-9.156nA	67.6mΩ	-109.8V	-9.161nA	67.0mΩ
9	-109.7V	-8.922nA	68.6mΩ	-109.4V	-8.963nA	67.4mΩ
10	-108.4V	-8.953nA	68.6mΩ	-108.6V	-9.121nA	66.9mΩ
11	-109.9V	-9.162nA	68.5mΩ	-109.3V	-9.165nA	68.9mΩ
12	-108.0V	-9.119nA	68.1mΩ	-108.2V	-9.086nA	68.9mΩ
13	-108.7V	-9.100nA	67.3mΩ	-109.3V	-9.024nA	67.2mΩ
14	-108.1V	-9.135nA	67.7mΩ	-108.7V	-9.181nA	67.8mΩ
15	-108.7V	-8.959nA	68.7mΩ	-108.1V	-8.867nA	68.7mΩ
16	-108.2V	-9.179nA	67.1mΩ	-108.3V	-8.914nA	68.4mΩ
17	-109.8V	-9.235nA	68.5mΩ	-109.2V	-9.241nA	68.6mΩ
18	-109.9V	-9.232nA	66.6mΩ	-109.5V	-9.080nA	67.2mΩ
19	-110.0V	-9.136nA	68.8mΩ	-109.9V	-9.160nA	67.8mΩ
20	-108.7V	-8.871nA	68.9mΩ	-109.4V	-8.851nA	67.7mΩ
21	-109.9V	-9.129nA	67.9mΩ	-109.0V	-9.040nA	67.1mΩ
22	-110.0V	-8.898nA	67.2mΩ	-109.6V	-9.131nA	68.1mΩ
23	-109.9V	-9.161nA	68.0mΩ	-109.0V	-9.056nA	67.1mΩ
24	-108.4V	-9.122nA	68.2mΩ	-109.8V	-9.062nA	66.8mΩ
25	-109.8V	-9.032nA	66.7mΩ	-108.6V	-8.947nA	67.7mΩ
26	-109.5V	-8.970nA	66.7mΩ	-109.9V	-8.902nA	67.2mΩ
27	-108.7V	-8.908nA	67.0mΩ	-108.9V	-8.946nA	68.6mΩ
28	-108.6V	-8.921nA	67.6mΩ	-109.5V	-9.011nA	66.8mΩ
29	-108.1V	-9.157nA	68.0mΩ	-108.7V	-8.883nA	68.9mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-108.4V	-9.205nA	68.0mΩ	-109.3V	-8.898nA	66.6mΩ
31	-108.3V	-9.121nA	68.2mΩ	-108.7V	-9.041nA	67.8mΩ
32	-109.6V	-9.100nA	67.3mΩ	-108.7V	-9.222nA	66.9mΩ
33	-109.2V	-8.932nA	68.5mΩ	-108.7V	-8.998nA	66.9mΩ
34	-109.2V	-9.047nA	67.6mΩ	-109.0V	-8.866nA	66.9mΩ
35	-108.7V	-9.118nA	68.9mΩ	-109.8V	-8.887nA	67.8mΩ
36	-109.0V	-8.849nA	67.0mΩ	-108.7V	-9.230nA	68.2mΩ
37	-109.3V	-9.216nA	66.8mΩ	-109.1V	-9.076nA	66.7mΩ
38	-108.7V	-9.227nA	67.5mΩ	-108.2V	-8.896nA	68.6mΩ
39	-110.0V	-9.183nA	68.6mΩ	-109.4V	-8.957nA	68.7mΩ
40	-109.1V	-8.993nA	68.4mΩ	-109.8V	-9.176nA	68.6mΩ
41	-109.6V	-9.165nA	68.7mΩ	-108.9V	-9.177nA	67.0mΩ
42	-110.0V	-9.158nA	68.6mΩ	-108.8V	-9.151nA	67.4mΩ
43	-108.6V	-9.000nA	67.3mΩ	-109.6V	-8.928nA	67.3mΩ
44	-109.9V	-9.075nA	66.7mΩ	-108.8V	-9.204nA	68.9mΩ
45	-109.3V	-9.211nA	68.4mΩ	-109.9V	-8.849nA	68.3mΩ
46	-108.5V	-9.019nA	68.5mΩ	-108.4V	-9.207nA	67.5mΩ
47	-109.6V	-9.028nA	66.6mΩ	-108.1V	-8.904nA	67.0mΩ
48	-109.1V	-8.956nA	67.0mΩ	-107.9V	-8.913nA	68.8mΩ
49	-108.3V	-9.106nA	66.9mΩ	-108.1V	-9.070nA	67.4mΩ
50	-109.0V	-8.973nA	66.6mΩ	-108.3V	-9.137nA	67.5mΩ
51	-108.3V	-8.868nA	67.5mΩ	-108.8V	-9.122nA	67.0mΩ
52	-108.2V	-9.248nA	67.0mΩ	-108.4V	-9.120nA	66.6mΩ
53	-108.0V	-9.234nA	67.7mΩ	-108.1V	-9.082nA	66.6mΩ
54	-107.9V	-8.852nA	68.5mΩ	-109.7V	-8.902nA	66.6mΩ
55	-108.2V	-9.162nA	67.1mΩ	-109.3V	-8.883nA	66.8mΩ
56	-108.1V	-9.065nA	68.6mΩ	-109.7V	-9.119nA	66.8mΩ
57	-109.7V	-8.851nA	68.4mΩ	-108.1V	-9.097nA	66.9mΩ
58	-109.8V	-9.100nA	67.3mΩ	-109.5V	-8.911nA	68.4mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2019.02.11 ~ 2019.03.26
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-109.7V	-9.123nA	69.0mΩ	-109.8V	-8.882nA	67.8mΩ
60	-108.1V	-8.868nA	68.7mΩ	-108.0V	-9.236nA	67.4mΩ
61	-108.9V	-9.168nA	68.3mΩ	-108.1V	-9.208nA	66.7mΩ
62	-109.0V	-8.861nA	67.1mΩ	-108.2V	-9.041nA	68.2mΩ
63	-108.5V	-9.198nA	66.7mΩ	-109.4V	-8.857nA	67.4mΩ
64	-108.6V	-9.229nA	67.0mΩ	-109.4V	-8.900nA	68.3mΩ
65	-110.0V	-9.062nA	66.8mΩ	-109.0V	-9.126nA	69.0mΩ
66	-109.1V	-9.153nA	68.5mΩ	-109.3V	-8.989nA	67.3mΩ
67	-108.7V	-9.194nA	67.3mΩ	-109.6V	-9.097nA	68.4mΩ
68	-109.3V	-8.876nA	66.9mΩ	-108.0V	-9.051nA	67.1mΩ
69	-109.5V	-9.148nA	67.3mΩ	-109.3V	-9.097nA	67.1mΩ
70	-108.8V	-9.106nA	67.6mΩ	-108.7V	-9.026nA	66.9mΩ
71	-108.6V	-9.062nA	68.1mΩ	-109.4V	-8.916nA	66.6mΩ
72	-108.4V	-9.248nA	67.7mΩ	-110.0V	-9.122nA	67.5mΩ
73	-108.2V	-9.078nA	68.9mΩ	-108.4V	-9.185nA	67.2mΩ
74	-109.4V	-9.172nA	68.7mΩ	-108.8V	-9.191nA	67.1mΩ
75	-108.0V	-9.197nA	67.7mΩ	-109.0V	-8.930nA	68.2mΩ
76	-109.9V	-8.970nA	66.6mΩ	-109.6V	-8.945nA	67.0mΩ
77	-108.7V	-9.068nA	67.0mΩ	-108.3V	-8.852nA	68.3mΩ

Made By: Leo Hsia

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T190328-15P10
Part No : SSD15P10-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : V(BR)DSS >-100V@ID=-250μA ；IDSS < -1μA@VDS=-80V
RDS(ON) < 90mΩ@VGS=-10V, ID=-4.5A
Test Condition: 245℃ ± 5℃, 5Sec
Test Date: 2019.03.27
Test Standard : JESD22 STANDER Method-B102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-109.9V	-9.132nA	67.5mΩ	-108.6V	-8.993nA	67.8mΩ
2	-108.6V	-8.881nA	68.4mΩ	-108.4V	-9.079nA	68.3mΩ
3	-108.2V	-9.220nA	68.0mΩ	-109.8V	-9.151nA	69.0mΩ
4	-110.0V	-8.940nA	67.7mΩ	-108.4V	-8.942nA	68.4mΩ
5	-109.0V	-9.075nA	67.2mΩ	-109.3V	-9.127nA	68.8mΩ
6	-109.4V	-8.938nA	67.7mΩ	-109.3V	-9.009nA	67.5mΩ
7	-107.9V	-9.082nA	67.1mΩ	-109.3V	-8.941nA	67.5mΩ
8	-109.6V	-9.141nA	67.8mΩ	-108.7V	-8.857nA	68.5mΩ
9	-110.0V	-9.116nA	68.5mΩ	-109.9V	-8.885nA	67.7mΩ
10	-109.6V	-8.921nA	66.9mΩ	-107.9V	-9.009nA	66.7mΩ

Made By: Leo Hsia

Approval: Peter Yang